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REISSUE

T. Roots

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant:	Leonard H. Bieman	Examiner:	Unknown
Serial No.:	Unknown	Group Art Unit:	Unknown
Filed:	Herewith	Docket:	139.032USR
Title:	SCANNING PHASE MEASURING METHOD AND SYSTEM FOR AN OBJECT AT A VISION STATION		

**PRELIMINARY AMENDMENT**

BOX PATENT APPLICATION  
Assistant Commissioner for Patents  
Washington, D.C. 20231

Please amend the above-identified reissue application as follows:

**IN THE CLAIMS**

Please amend claims 15, 18, and 26 of the patent, and add new claims 28-85 as follows  
(all claims are reprinted for the Examiner's convenience):

1. A method for high speed, scanning phase measuring of an object at a vision station to develop physical information associated with the object, the method comprising the steps of:
  - projecting a pattern of imagable electromagnetic radiation with at least one projector;
  - moving the object relative to the at least one projector at a substantially constant velocity at the vision station so as to scan the projected pattern of electromagnetic radiation across a surface of the object to generate an imagable electromagnetic radiation signal;
  - receiving the imagable electromagnetic radiation signal from the surface of the object with a detector having a plurality of separate detector elements which are substantially uniformly spaced;
  - maintaining the at least one projector and the detector in a substantially fixed relation to each other;
  - measuring an amount of radiant energy in the received electromagnetic radiation signal with the detector wherein each of the detector elements produce an image having a different phase of the same scanned surface based on the measurement; and

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